



8085A/8085A-2 SINGLE CHIP 8-BIT N-CANNEL MICROPROCESSORS

- Single +5V Power Supply
- 100% Software Compatible with 8080A
- 1.3 μ s Instruction Cycle (8085A);
0.8 μ s (8085A-2)
- On-Chip Clock Generator (with External Crystal, LC or RC Network)
- On-Chip System Controller; Advanced Cycle Status Information Available for Large System Control
- Four Vectored Interrupt Inputs (One is Non-Maskable) Plus an 8080A-Compatible Interrupt
- Serial In/Serial Out Port
- Decimal, Binary and Double Precision Arithmetic
- Direct Addressing Capability to 64k Bytes of Memory

The Intel® 8085A is a complete 8 bit parallel Central Processing Unit (CPU). Its instruction set is 100% software compatible with the 8080A microprocessor, and it is designed to improve the present 8080A's performance by higher system speed. Its high level of system integration allows a minimum system of three IC's [8085A (CPU), 8156 (RAM/IO) and 8355/8755A (ROM/PROM/IO)] while maintaining total system expandability. The 8085A-2 is a faster version of the 8085A.

The 8085A incorporates all of the features that the 8224 (clock generator) and 8228 (system controller) provided for the 8080A, thereby offering a high level of system integration.

The 8085A uses a multiplexed data bus. The address is split between the 8 bit address bus and the 8 bit data bus. The on-chip address latches of 8155/8156/8355/8755A memory products allow a direct interface with the 8085A.

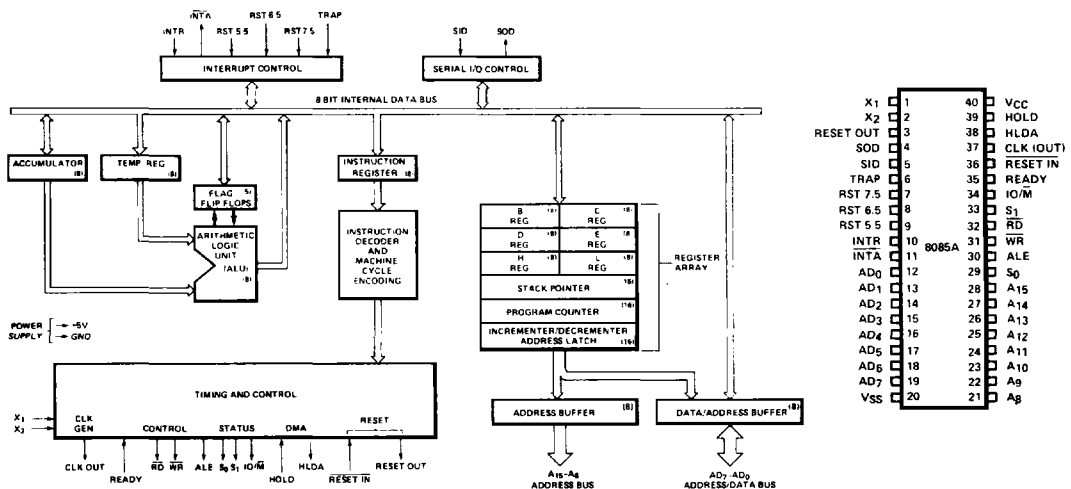


Figure 1. 8085A CPU Functional Block Diagram

Figure 2. 8085A Pin Configuration

ABSOLUTE MAXIMUM RATINGS*

Ambient Temperature Under Bias. 0°C to 70°C
 Storage Temperature -65°C to +150°C
 Voltage on Any Pin
 With Respect to Ground -0.5V to +7V
 Power Dissipation 1.5 Watt

**NOTICE: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*

D.C. CHARACTERISTICS (T_A = 0°C to 70°C, V_{CC} = 0V ±5%, V_{SS} = 0V; unless otherwise specified)

Symbol	Parameter	Min.	Max.	Units	Test Conditions
V _{IL}	Input Low Voltage	-0.5	+0.8	V	
V _{IH}	Input High Voltage	2.0	V _{CC} +0.5	V	
V _{OL}	Output Low Voltage		0.45	V	I _{OL} = 2mA
V _{OH}	Output High Voltage	2.4		V	I _{OH} = -400μA
I _{CC}	Power Supply Current		170	mA	
I _{IL}	Input Leakage		±10	μA	0 ≤ V _{IN} ≤ V _{CC}
I _{LO}	Output Leakage		±10	μA	0.45V ≤ V _{out} ≤ V _{CC}
V _{ILR}	Input Low Level, RESET	-0.5	+0.8	V	
V _{IHR}	Input High Level, RESET	2.4	V _{CC} +0.5	V	
V _{HY}	Hysteresis, RESET	0.25		V	

A.C. CHARACTERISTICS ($T_A = 0^\circ\text{C}$ to 70°C , $V_{CC} = 0\text{V} \pm 5\%$, $V_{SS} = 0\text{V}$)

Symbol	Parameter	8085A ^[2]		8085A-2 ^[2]		Units
		Min.	Max.	Min.	Max.	
t_{CYC}	CLK Cycle Period	320	2000	200	2000	ns
t_1	CLK Low Time (Standard CLK Loading)	80		40		ns
t_2	CLK High Time (Standard CLK Loading)	120		70		ns
t_r, t_f	CLK Rise and Fall Time		30		30	ns
t_{XKR}	X_1 Rising to CLK Rising	30	120	30	100	ns
t_{XKF}	X_1 Rising to CLK Falling	30	150	30	110	ns
t_{AC}	A_{8-15} Valid to Leading Edge of Control ^[1]	270		115		ns
t_{ACL}	A_{0-7} Valid to Leading Edge of Control	240		115		ns
t_{AD}	A_{0-15} Valid to Valid Data In		575		350	ns
t_{AFR}	Address Float After Leading Edge of READ (INTA)		0		0	ns
t_{AL}	A_{8-15} Valid Before Trailing Edge of ALE ^[1]	115		50		ns
t_{ALL}	A_{0-7} Valid Before Trailing Edge of ALE	90		50		ns
t_{ARY}	READY Valid from Address Valid		220		100	ns
t_{CA}	Address (A_{8-15}) Valid After Control	120		60		ns
t_{CC}	Width of Control Low (RD, WR, INTA) Edge of ALE	400		230		ns
t_{CL}	Trailing Edge of Control to Leading Edge of ALE	50		25		ns
t_{DW}	Data Valid to Trailing Edge of WRITE	420		230		ns
t_{HABE}	HLDA to Bus Enable		210		150	ns
t_{HABF}	Bus Float After HLDA		210		150	ns
t_{HACK}	HLDA Valid to Trailing Edge of CLK	110		40		ns
t_{HDL}	HOLD Hold Time	0		0		ns
t_{HDS}	HOLD Setup Time to Trailing Edge of CLK	170		120		ns
t_{INH}	INTR Hold Time	0		0		ns
t_{INS}	INTR, RST, and TRAP Setup Time to Falling Edge of CLK	160		150		ns
t_{IA}	Address Hold Time After ALE	100		50		ns
t_{LC}	Trailing Edge of ALE to Leading Edge of Control	130		60		ns
t_{LCK}	ALE Low During CLK High	100		50		ns
t_{LDR}	ALE to Valid Data During Read		460		270	ns
t_{LDW}	ALE to Valid Data During Write		200		120	ns
t_{LL}	ALE Width	140		80		ns
t_{LRY}	ALE to READY Stable		110		30	ns

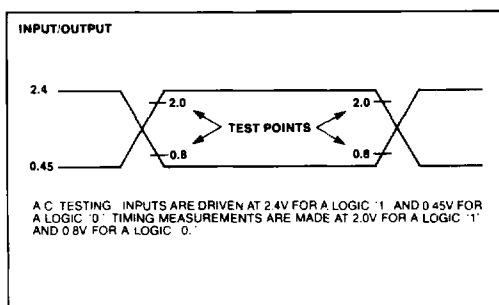
A.C. CHARACTERISTICS (Continued)

Symbol	Parameter	8085A ^[2]		8085A-2 ^[2]		Units
		Min.	Max.	Min.	Max.	
t _{RAE}	Trailing Edge of $\overline{\text{READ}}$ to Re-Enabling of Address	150		90		ns
t _{RD}	$\overline{\text{READ}}$ (or $\overline{\text{INTA}}$) to Valid Data		300		150	ns
t _{RV}	Control Trailing Edge to Leading Edge of Next Control	400		220		ns
t _{RDH}	Data Hold Time After $\overline{\text{READ}}$ $\overline{\text{INTA}}$ ^[7]	0		0		ns
t _{RYH}	READY Hold Time	0		0		ns
t _{RYS}	READY Setup Time to Leading Edge of CLK	110		100		ns
t _{WD}	Data Valid After Trailing Edge of $\overline{\text{WRITE}}$	100		60		ns
t _{WDL}	LEADING Edge of $\overline{\text{WRITE}}$ to Data Valid		40		20	ns

NOTES:

1. A₈-A₁₅ address Specs apply to IO/ $\overline{\text{M}}$, S₀, and S₁ except A₈-A₁₅ are undefined during T₄-T₆ of OF cycle whereas IO/ $\overline{\text{M}}$, S₀, and S₁ are stable.
2. Test conditions: t_{CYC} = 320 ns (8085A)/200 ns (8085A-2); C_L = 150 pF.
3. For all output timing where C_L = 150 pF use the following correction factors:
25 pF ≤ C_L < 150 pF: -0.10 ns/pF
150 pF < C_L ≤ 300 pF: +0.30 ns/pF
4. Output timings are measured with purely capacitive load.
5. All timings are measured at output voltage V_L = 0.8V, V_H = 2.0V, and 1.5V with 20 ns rise and fall time on inputs.
6. To calculate timing specifications at other values of t_{CYC} use Table 7.
7. Data hold time is guaranteed under all loading conditions.

A.C. TESTING INPUT, OUTPUT WAVEFORM



A.C. TESTING LOAD CIRCUIT

